Evaluation of Life Testing Schemes

Paul Britton, NASA Kelby Starchman, Bastion

paul.t.britton@nasa.gov kelby.l.starchman@nasa.gov

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Background

- We will explore the age-old question: What reliability can we infer from a qualification life test with zero failures? Moreover, we will offer an alternate and more pragmatic way to approach this problem.
- Notional Situation:
 - If we test 4 Units to 2x Lives without failure, can we infer the same reliability as if we tested 1 Unit to 4x Lives?
- Ground rules:
 - The life distribution is Weibull
 - The failure mode of interest is wear-out
 - The reliability requirement is 0.99
 - The Notional Program has high tolerance for risk

Weibull Distribution Overview

$$f(x) = \frac{\beta}{\eta} \left(\frac{x}{\eta}\right)^{\beta-1} e^{-(xT\eta)^{\beta}}$$

$$F(x) \stackrel{\text{def}}{=} \mathfrak{D}_{0} f \mathfrak{H} dt = 1 - e^{\frac{\xi}{\tau} xT\mathfrak{H}^{\beta}}$$

F(x)

Example Weibull plots for beta = 4, eta = 3

f(x) 🔺

- beta represents the acceleration of failure rate
- eta represents characteristic life independent of beta •

Failure Space

Note1: $F(\eta) \cong 0.63$ and $S(\eta) \cong 0.37$

Note2: For $\beta > 1$, h(x) increases over time

S(x) = 1 - F(x)

h(x) = f(x) / S(x)



Problem Statement

• Given that design life qualification is successful, what reliability can we infer?

Misconception: Design life qualification tests informs reliability

Default Approach

- This requires finding the optimal Weibull fit using the data from the qualification test
- Mathematically, this optimization problem has unbounded solutions, at best, if not undefined
- However, if we fix the shape parameter beta, then a solution for eta can be found; and reliability can be calculated at a given confidence level
- **The issue** with this approach is that it makes a weakly supported yet a very specific defining assumption to obtain a solution

A More Pragmatic and Useful Approach

- Qualification success criteria is pass/fail in nature
 - To minimize false positive and false negative test errors we follow the structured procedure below
- Use engineering judgment and a bootstrapping strategy to make data driven steps towards useful conclusions
 - Step 0) Solicit Program reliability thresholds and risk posture
 - Step 1) Collect development and failure mode data
 - Step 2) Perform Weibull Analysis on anticipated Qualification test results
 - Step 3) Construct contour overlays based on Weibull Analysis
 - Step 4) Evaluate Qualification Test Effectiveness against objective measures
 - Step 5) Iterate on Qualification success criteria, if needed

Measuring Reliability from Data

- Survival curve fits, based on three sets of hypothetical 4-Unit Qualification Tests using Median Rank Regression
- For these sets, the ranges beta = [2, 6] and eta = [1.5, 4.5] establish a focus region of anticipated Weibull parameters



Visualization of Qualification Effectiveness



- 1x Mission Reliability (S(1)) overlaid onto Probability of Successful Qualification (S(x)^n) reveals the landscape of false positives and false negatives for different qualification test schemes
- The focus region (beta = [2, 6] and eta = [1.5, 4.5]), derived from data that is likely to be representative of anticipated designs

Revised Problem Statement

• Optimize Cost, Schedule and Reliability Qualification Test Effectiveness

 Solution: Given a reliability threshold and risk posture for false negatives and false positive risk, contour overlays can aid in objectively measure the effectiveness of a qualification test scheme

Summary



Backup

Uncertainty in Reliability Estimation

- Comparison of notional Median Rank Regression survival curve fits with 90% confidence intervals and (Failure Time, Median Rank) points
- Estimated uncertainty is sensitive to the sample size, goodness of fit, and variability in sampled values















20u-1x